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					Application Number	10/031,081			
	INFO	RMATION	1 DISC	LOSURE	Filing Date	January 16, 2002			
	STAT	EMENT E	BY APF	PLICANT	First Named Inventor	Osamu TERASAKI et al.			
					Group Art Unit	2881			
(use as many sheets as necessary)					Examiner Name	Bernard E. Souw			
abla	Sheet	1	of	1	Attorney Docket Number	TAKIT-163			

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	l	U.S. Patent Document			Date of Publication of Cited	Dance Calumna Linea Whom		
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Examine Signatur		Bernard Souw	Date Considered	05/01/03	-	

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